

# Search Notes



Application/Control No.

10/572,702

Examiner

Tran N. Nguyen

Applicant(s)/Patent under Reexamination

FUTAMI, TOSHIHIKO

Art Unit

2834

## SEARCHED

Class	Subclass	Date	Examiner
310	156.48	4/11/07	JNN
	156.53		
	156.54		
	156.56		
	156.57		
	261		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
310	all above	4/13/07	JNN

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
H02K 1/27 24 22	4/12/07	JNN
H02K 21/12 14 16		
Text search Interferen search	4/13/07	JNN